Product/Process Change Notice - PCN 18_0171 Rev. C

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This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

Note: Revised fields are indicated by a red field name. See Appendix B for revision history.

PCN Title: ADA4522 Die Revision

Publication Date: 20-Aug-2020

Effectivity Date: 20-Aug-2020 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:
Updating qualification results.

Description Of Change:

Changes to the Metal 1 / Via / Metal 2 layers. All models will be affected.

Reason For Change:

Improved power on start-up robustness for both high source impendence configurations and high supply current conditions.

Impact of the change (positive or negative) on fit, form, function & reliability:

No Impact to fit, form or function. Reliability improved to cover application with power on start-up and high source impedance.

Product Identification *(this section will describe how to identify the changed material)*

Material will be separated by date code for conversion to the new die. ADA4522-2 cutover date was 1918.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

Supporting Documents

Attachment 1: **Type**: Qualification Results Summary

ADI_PCN_18_0171_Rev_C_ADA4522-1_Qualification_Results_Summary.pdf

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Attachment 2: **Type**: Qualification Results Summary

ADI_PCN_18_0171_Rev_C_ADA4522-2_Qualification_Results_Summary.pdf

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Attachment 3: **Type**: Qualification Results Summary

ADI_PCN_18_0171_Rev_C_ADA4522-4_Qualification_Results_Summary.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas: PCN_Americas@analog.com	**Europe:** PCN_Europe@analog.com	**Japan:** PCN_Japan@analog.com	**Rest of Asia:** PCN_ROA@analog.com

Appendix A - Affected ADI Models

Existing Parts - Product Family / Model Number (18)

ADA4522-1 / ADA4522-1ARMZ	ADA4522-1 / ADA4522-1ARMZ-R7	ADA4522-1 / ADA4522-1ARMZ-RL	ADA4522-1 / ADA4522-1ARZ	ADA4522-1 / ADA4522-1ARZ-R7
ADA4522-1 / ADA4522-1ARZ-RL	ADA4522-2 / ADA4522-2ARMZ	ADA4522-2 / ADA4522-2ARMZ-R7	ADA4522-2 / ADA4522-2ARMZ-RL	ADA4522-2 / ADA4522-2ARZ
ADA4522-2 / ADA4522-2ARZ-R7	ADA4522-2 / ADA4522-2ARZ-RL	ADA4522-4 / ADA4522-4ARUZ	ADA4522-4 / ADA4522-4ARUZ-R7	ADA4522-4 / ADA4522-4ARUZ-RL
ADA4522-4 / ADA4522-4ARZ	ADA4522-4 / ADA4522-4ARZ-R7	ADA4522-4 / ADA4522-4ARZ-RL		

Appendix B - Revision History

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	20-Dec-2018	28-Feb-2019	Initial Release.
Rev. A	20-May-2019	22-Aug-2019	Add parts. Add Qualification Results for ADA4522-2. Add Qualification Plan for ADA4522-1.
Rev. B	24-Feb-2020	28-May-2020	Add parts ADA4522-4. Add Qualification Results for ADA4522-1. Add Qualification Plan for ADA4522-4. Add conversion date for ADA4522-2.
Rev. C	20-Aug-2020	20-Aug-2020	Updating qualification results.

Qualification Results Summary of ADA4522-4 Die Revision

QUALIFICATION PLAN / STATUS			
TEST	**SPECIFICATION**	**SAMPLE SIZE**	**RESULTS**
Solder Heat Resistance (SHR)[1]	JEDEC *J-STD-020*	1 x 30	Pass
Latch-Up	JEDEC *JESD78*	3/test	Pass ±200 mA, ±41.25 V
Electrostatic Discharge *Human Body Model*[2]	ESDA/JEDEC *JS-001-2011*	3/voltage	Pass ±3000 V
Electrostatic Discharge *Field-Induced Charged Device Model*	JEDEC *JS-002*	3/voltage	Pass ±1250 V

[1] Preconditioned per JEDEC J-STD-020 Level 1

ADA4522-2 Die Revision

Qualification Results Summary of ADA4522-2 Die Revision

QUALIFICATION PLAN / STATUS			
TEST	**SPECIFICATION**	**SAMPLE SIZE**	**RESULTS**
Solder Heat Resistance (SHR)[1]	JEDEC *J-STD-020*	1 x 30	Pass
Latch-Up	JEDEC *JESD78*	3/test	Pass ±200 mA, ±41.25 V
Electrostatic Discharge *Human Body Model*[2]	ESDA/JEDEC *JS-001-2011*	3/voltage	Pass ±4000 V
Electrostatic Discharge *Field-Induced Charged Device Model*	JEDEC *JS-002*	3/voltage	Pass ±1250 V

[1] Preconditioned per JEDEC J-STD-020 Level 1

Qualification Results Summary of ADA4522-1 Die Revision

QUALIFICATION PLAN / STATUS			
TEST	**SPECIFICATION**	**SAMPLE SIZE**	**RESULTS**
Solder Heat Resistance (SHR)[1]	JEDEC *J-STD-020*	1 x 30	Pass
Latch-Up	JEDEC *JESD78*	3/test	Pass ±200 mA, ±41.25 V
Electrostatic Discharge *Human Body Model*[2]	ESDA/JEDEC *JS-001-2011*	3/voltage	Pass ±3500 V
Electrostatic Discharge *Field-Induced Charged Device Model*	JEDEC *JS-002*	3/voltage	Pass ±1250 V

[1] Preconditioned per JEDEC J-STD-020 Level 1